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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
10/737,370	10/737,370 12/16/2003		N1085-00250 [TSMC2003-082	5375		
8933 75	90 10/04/2004	EXAM	EXAMINER			
DUANE MORRIS, LLP IP DEPARTMENT			DOUGHERTY,	DOUGHERTY, ANTHONY T		
ONE LIBERTY PLACE			ART UNIT	PAPER NUMBER		
PHILADELPHI	IA, PA 19103-7396	2863				

DATE MAILED: 10/04/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application	n No.	Applicant(s)			
		10/737,37	0	YUEN ET AL.			
Office Action Summary		Examiner		Art Unit			
		Anthony T	Dougherty	2863			
Period f	The MAILING DATE of this communication or Reply	n appears on the	cover sheet with th	e correspondence addi	ress		
A SH THE - Exte after - If th - If NO - Failt Any	MORTENED STATUTORY PERIOD FOR REMAILING DATE OF THIS COMMUNICATION (S) MONTHS from the mailing date of this communication is period for reply specified above, the maximum statutory pure to reply within the set or extended period for reply will, by reply received by the Office later than three months after the need patent term adjustment. See 37 CFR 1.704(b).	ON. FR 1.136(a). In no eve on. , a reply within the statu period will apply and wi statute, cause the appl	nt, however, may a reply be tory minimum of thirty (30) I expire SIX (6) MONTHS fi ication to become ABANDO	e timely filed days will be considered timely. rom the mailing date of this com DNED (35 U.S.C. § 133).	imunication.		
Status	·						
1)🛛	Responsive to communication(s) filed on 17 May 2004.						
2a)□	2a) ☐ This action is FINAL . 2b) ☑ This action is non-final.						
3)	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.						
Disposit	ion of Claims						
5)⊠	<u> </u>						
Applicat	tion Papers						
9) The specification is objected to by the Examiner. 10) ☑ The drawing(s) filed on 17 May 2004 is/are: a) ☑ accepted or b) □ objected to by the Examiner.							
•	Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).						
11)	Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d). 1) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.						
Priority	under 35 U.S.C. § 119						
12)□ a)	Acknowledgment is made of a claim for for All b) Some * c) None of: 1. Certified copies of the priority docu 2. Certified copies of the priority docu 3. Copies of the certified copies of the application from the International B	ments have bee ments have bee e priority docume tureau (PCT Rule	n received. n received in Applic ents have been rece e 17.2(a)).	cation No eived in this National S	itage		
Attachmer	• •						
2)	ce of References Cited (PTO-892) ce of Draftsperson's Patent Drawing Review (PTO-94 mation Disclosure Statement(s) (PTO-1449 or PTO/5 er No(s)/Mail Date		4) Interview Summ Paper No(s)/Ma 5) Notice of Inform 6) Other:		152)		

Application/Control Number: 10/737,370

Art Unit: 2863

DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 2. Claims 1-5, and 7-11 rejected under 35 U.S.C. 102(b) as being anticipated by U.S. Patent No. 4,752,898 to Koenig.

With regard to claims 1 and 7 Koenig discloses apparatus for detecting wafer flat shift (see abstract), with a plurality of sensors in a power supply circuit for shutting off wafer fabrication equipment (see column 3 line 18-40), the sensor detecting a shift in wafer flat position (see column 3 line 61-64), and the power supply circuit shutting off the wafer fabrication equipment when the shift exceeds a set amount (see column 3 line 18-31).

With regard to claims 2 and 8, and applying the rejection of claims 1 and 7 above, Koenig discloses the sensors adjusted to detect a wafer flat shift in a plurality of directions of angular displacement (see column 3 line 64 through column 4 line 34).

With regard to claims 3 and 10, and applying the rejection of claims 1 and 7 above, Koenig discloses the sensors adjusted to detect a wafer flat shift in a range of (2)(0.9°) to (5)(0.9°) angular displacement (see column 4 line 23-32).

With regard to claim 4, and applying the rejection of claim 1 above, Koenig discloses a

frame (see Figure 1), and an adjustable mounting mechanism mounting each sensor on the frame

for adjustment along orthogonal axes (see column 3 line 36-60).

With regard to claim 5, and applying the rejection of claim 1 above, Koenig discloses a

frame (see Figure 1), and sensors being adjustably mounted on the frame (see column 3 line 36-

60).

With regard to claim 9, and applying the rejection of claim 7 above, Koenig discloses

detecting the wafer flat shift by optical beam sensors (see column 3 line 36-60).

With regard to claim 11, and applying the rejection of claim 7 above, Koenig discloses

detecting the wafer flat shift by optical beam sensors and adjusting the position of the sensors

(see column 3 line 36-60).

Allowable Subject Matter

3. Claims 15-20 allowed.

4. Claims 6, and 12-14 objected to as being dependent upon a rejected base claim, but

would be allowable if rewritten in independent form including all of the limitations of the base

claim and any intervening claims.

5. The following is a statement of reasons for the indication of allowable subject matter:

The primary reason for the allowance of claims 6, 12-14, and 15-20 is the inclusion of the limitations of an apparatus for detecting a wafer flat shift which includes a relay activated by signals from sensors detecting an angular displacement of a wafer flat, a solenoid operated by the relay to open a door to release a corresponding wafer for further fabrication, and when a wafer flat shift is sensed shut off the sensors which activate the door. It is these limitations found in each of the claims, as they are claimed in the combination, that has not been found, taught or suggested by the prior art of record which makes these claims allowable over the prior art.

Conclusion

- 6. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.
- U.S. Patent No. 4,880,348 to Baker et al. because it teaches a device for centering and rotating a wafer flight using optical beam sensors.
- U.S. Patent No. 4,449,885 to Hertel et al. because it teaches a wafer transfer assembly with wafer flat adjustment.
- U.S. Patent No. 5,452,521 to Niewmierzycki because it teaches detection and correction of angular displacement of a wafer using optical beam sensors.
- U.S. Patent No. 5,483,138 to Shmookler et al. because it teaches detecting and aligning the center of a wafer.
- U.S. Patent No. 5,725,664 to Nanbu et al. because it teaches wafer flat detection and alignment inside a chamber with a door that controls air discharge of the chamber

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Anthony T. Dougherty whose telephone number is (571) 272-2273. The examiner can normally be reached on Monday through Friday from 8 to 5.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John E. Barlow can be reached on (571) 272-2269. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

atd

John Barlow
Supervisory Patent Examiner
Technology Center 2800